

SEMICAPS 5000

DIRECT TESTER-DOCKED WAFER PROBE SYSTEM



Features

- Wafer analysis using a combination of Laser Timing Probe (LTP), Scanning Optical Microscope (SOM) and Photon Emission Microscope (PEM)
- Eliminate the need for sorting, dicing and repackaging of the wafer
- Able to analyze at full tester speeds of up to 8 GHz
- Land more than 10,000 pins using a standard Production Probe Card
- RSIL option: compatible with full thickness, unthinned wafer



Docking with Advantest
V93000 Direct Probe™

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SEMICAPS
Excellence In Innovation